

**Search Notes**

Application/Control No.

10/517,517

Examiner

Steven S. Paik

Applicant(s)/Patent under  
Reexamination

DEMMELE ET AL.

Art Unit

2876

**SEARCHED**

Class	Subclass	Date	Examiner
235	379		
	380		
705	45	6/7/2007	SSP

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST		
Text search; see attached search history	6/7/2007	SSP